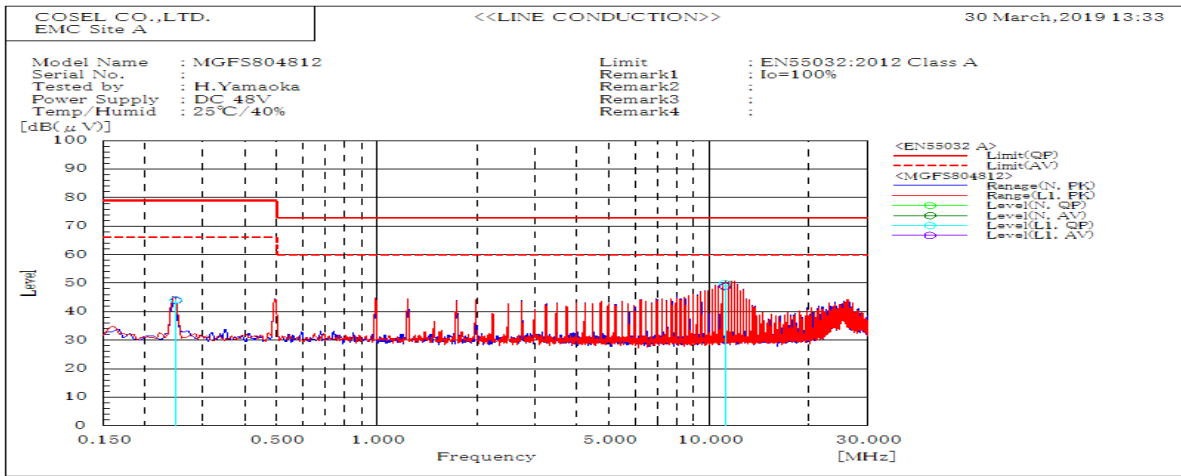
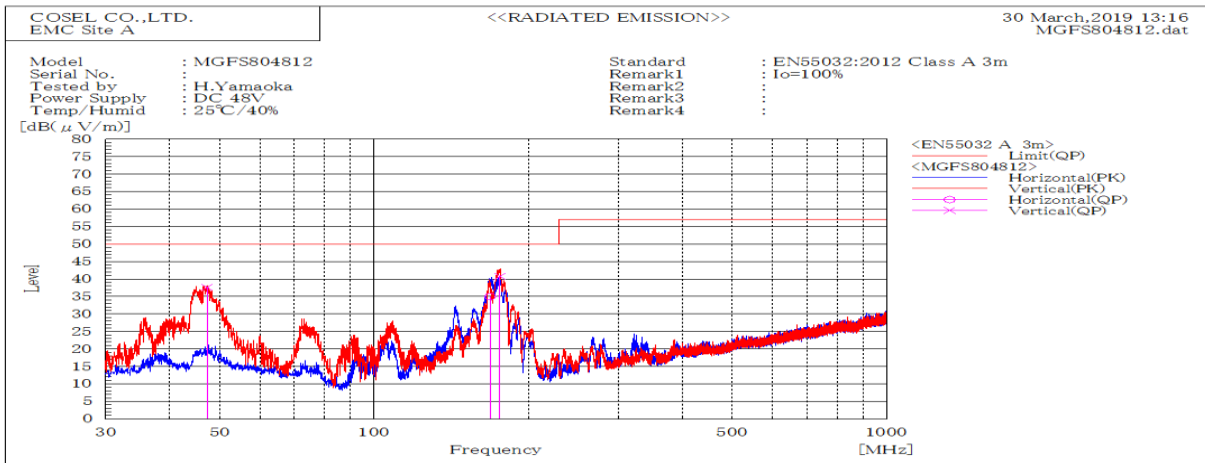


DATA SHEET		Date	23-Apr-19
Model	MGFS804812	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	H.Yamaoka



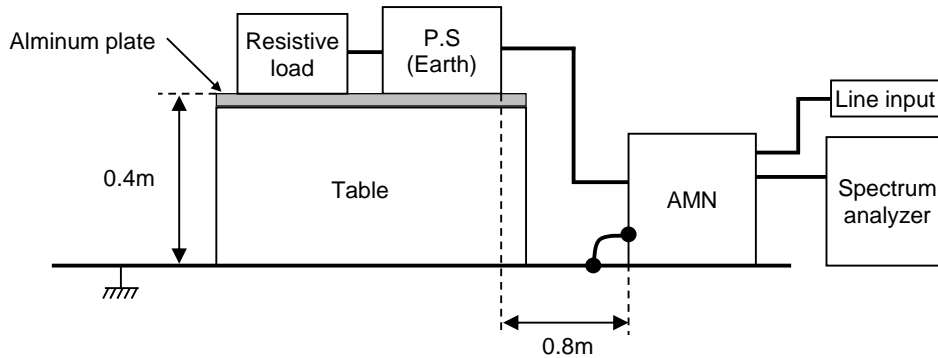
Frequency MHz	Line	Level		Limit		Margin		Pass/Fail	Remark
		dB(µV)		dB(µV)		dB			
		QP	AV	QP	AV	QP	AV		
11.173	L1	50	48.9	73	60	23	11.1	Pass	
0.248	L1	44.2	44	79	66	34.8	22	Pass	
11.163	N	50	48.9	73	60	23	11.1	Pass	



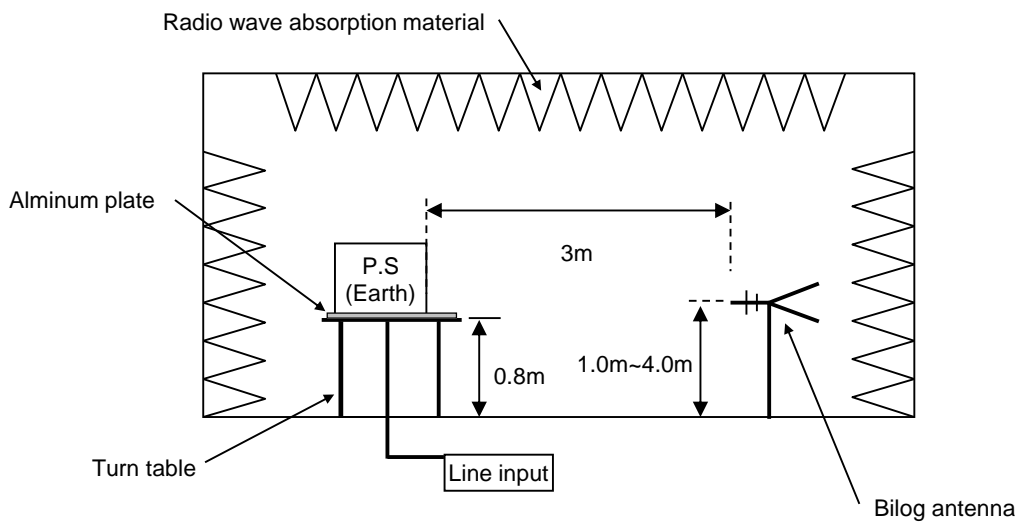
Frequency MHz	Polarization	Stability	Level		Margin dB	Pass/Fail	Height cm	Angle deg	Remark
			QP	QP					
176.162	V	Stable	40.7	50	9.3	Pass	103.3	216	
47.317	V	Stable	37.6	50	12.4	Pass	100	1.7	
168.51	H	Stable	35	50	15	Pass	162.3	190.2	

DATA SHEET		Date	23-Apr-19
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	H.Yamaoka

1. Line conduction



2. Radiated emission



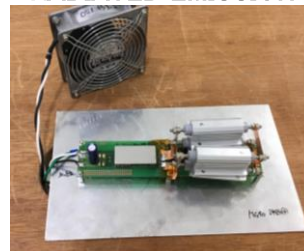
Conditions

Test : EMI
 Model Name : MGFS80□□

○Photographs of Test Set-Up
LINE CONDUCTION



RADIATED EMISSION



○Testing circuitry

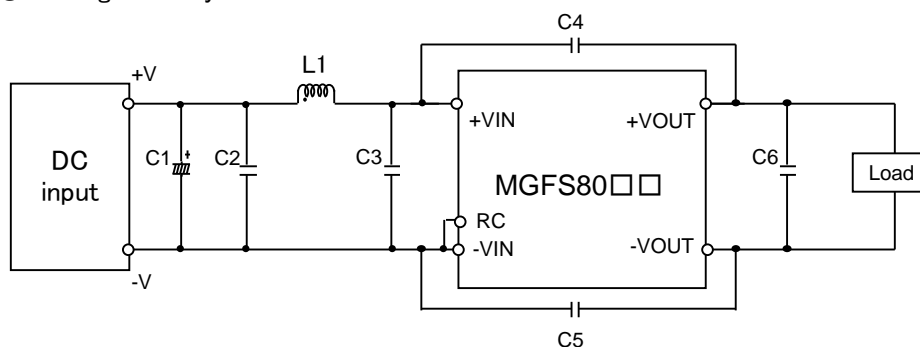


Fig.1 Testing circuitry

- C1 : MGFS8024□□ 63V 470 μ F Electrolytic capacitor (ELXseries NIPPON CHEMI-CON)
 MGFS8048□□ 100V 220 μ F Electrolytic capacitor (KYseries NIPPON CHEMI-CON)
- C2 : MGFS8024□□ 50V 10 μ F Ceramic capacitor (GRM32ER71H106K MURATA MANUFACTURING)
 MGFS8048□□ 100V 4.7 μ F Ceramic capacitor (HMK325C7475K TAIYOU YUDEN)
- C3 : MGFS8024□□ 50V 10 μ F Ceramic capacitor (GRM32ER71H106K MURATA MANUFACTURING)
 MGFS8048□□ 100V 4.7 μ F Ceramic capacitor (HMK325C7475K TAIYOU YUDEN)
- C4,C5 : MGFS8024□□ 2kV 2200pF Ceramic capacitor (GR443QR73D222KW01 MURATA MANUFACTURING)
 MGFS8048□□ 2kV 3300pF Ceramic capacitor (GR443QR73D332KW01 MURATA MANUFACTURING)
- C6 : MGFS8024□□ 25V 22 μ F Ceramic capacitor (GRM32ER71E226K MURATA MANUFACTURING)
 MGFS8048□□ 25V 22 μ F Ceramic capacitor (GRM32ER71E226K MURATA MANUFACTURING)
- L1 : MGFS8024□□ 12.0A 1.8 μ H Inductor (SRP7050TA-1R8M BOURNS)
 MGFS8048□□ 8.0A 3.3 μ H Inductor (SRP7050TA-3R3M BOURNS)